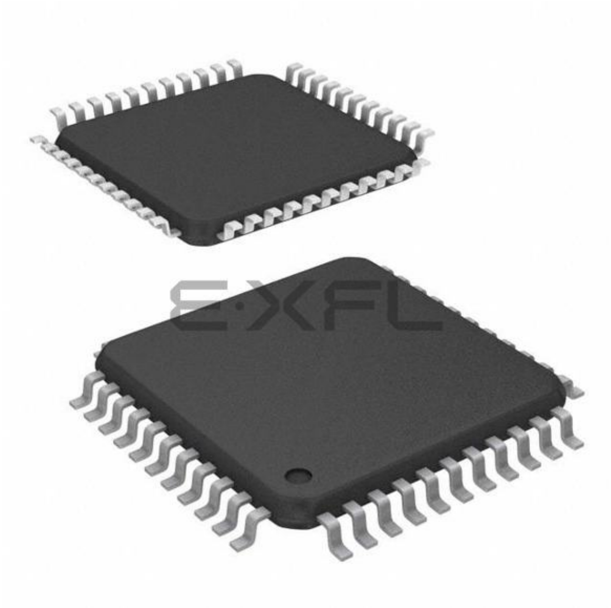


Understanding Embedded - CPLDs (Complex Programmable Logic Devices)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	10 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	2
Number of Macrocells	32
Number of Gates	600
Number of I/O	34
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	44-TQFP
Supplier Device Package	44-TQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm3032atc44-10

Table 2. MAX 3000A Speed Grades					
Device	**Speed Grade**				
	–4	**–5**	**–6**	**–7**	**–10**
EPM3032A	✓			✓	✓
EPM3064A	✓			✓	✓
EPM3128A		✓		✓	✓
EPM3256A				✓	✓
EPM3512A				✓	✓

The MAX 3000A architecture supports 100% transistor-to-transistor logic (TTL) emulation and high–density small-scale integration (SSI), medium-scale integration (MSI), and large-scale integration (LSI) logic functions. The MAX 3000A architecture easily integrates multiple devices ranging from PALs, GALs, and 22V10s to MACH and pLSI devices. MAX 3000A devices are available in a wide range of packages, including PLCC, PQFP, and TQFP packages. See Table 3.

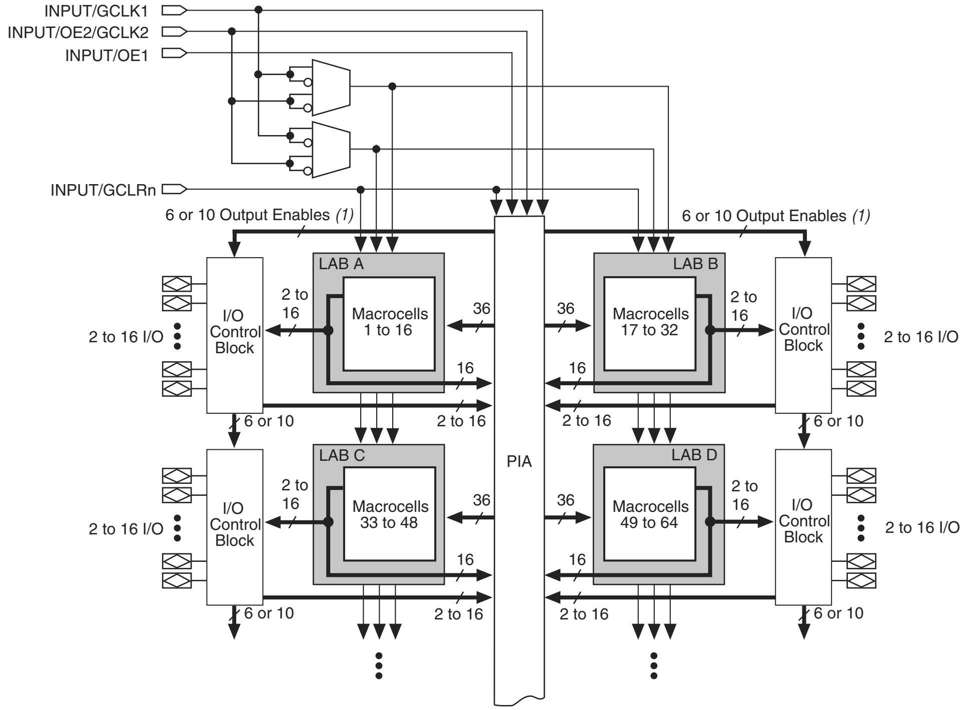
Table 3. MAX 3000A Maximum User I/O Pins Note (1)						
Device	**44–Pin PLCC**	**44–Pin TQFP**	**100–Pin TQFP**	**144–Pin TQFP**	**208–Pin PQFP**	**256-Pin FineLine BGA**
EPM3032A	34	34				
EPM3064A	34	34	66			
EPM3128A			80	96		98
EPM3256A				116	158	161
EPM3512A					172	208

Note:

(1) When the IEEE Std. 1149.1 (JTAG) interface is used for in–system programming or boundary–scan testing, four I/O pins become JTAG pins.

MAX 3000A devices use CMOS EEPROM cells to implement logic functions. The user–configurable MAX 3000A architecture accommodates a variety of independent combinatorial and sequential logic functions. The devices can be reprogrammed for quick and efficient iterations during design development and debugging cycles, and can be programmed and erased up to 100 times.

Figure 1. MAX 3000A Device Block Diagram



Note:

(1) EPM3032A, EPM3064A, EPM3128A, and EPM3256A devices have six output enables. EPM3512A devices have 10 output enables.

Logic Array Blocks

The MAX 3000A device architecture is based on the linking of high–performance LABs. LABs consist of 16–macrocell arrays, as shown in Figure 1. Multiple LABs are linked together via the PIA, a global bus that is fed by all dedicated input pins, I/O pins, and macrocells.

Each LAB is fed by the following signals:

- 36 signals from the PIA that are used for general logic inputs
- Global controls that are used for secondary register functions

Expander Product Terms

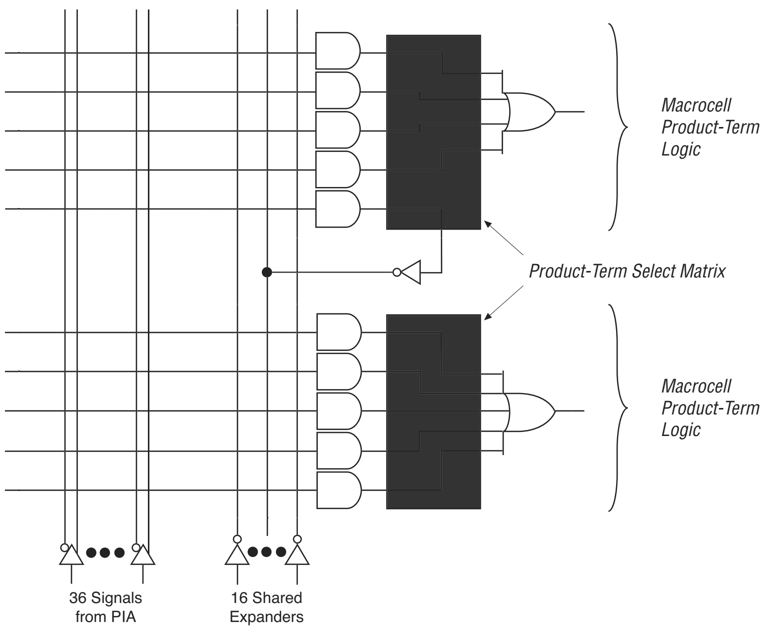
Although most logic functions can be implemented with the five product terms available in each macrocell, highly complex logic functions require additional product terms. Another macrocell can be used to supply the required logic resources. However, the MAX 3000A architecture also offers both shareable and parallel expander product terms ("expanders") that provide additional product terms directly to any macrocell in the same LAB. These expanders help ensure that logic is synthesized with the fewest possible logic resources to obtain the fastest possible speed.

Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. Shareable expanders incur a small delay (t_{SEXP}). Figure 3 shows how shareable expanders can feed multiple macrocells.

Figure 3. MAX 3000A Shareable Expanders

Shareable expanders can be shared by any or all macrocells in an LAB.



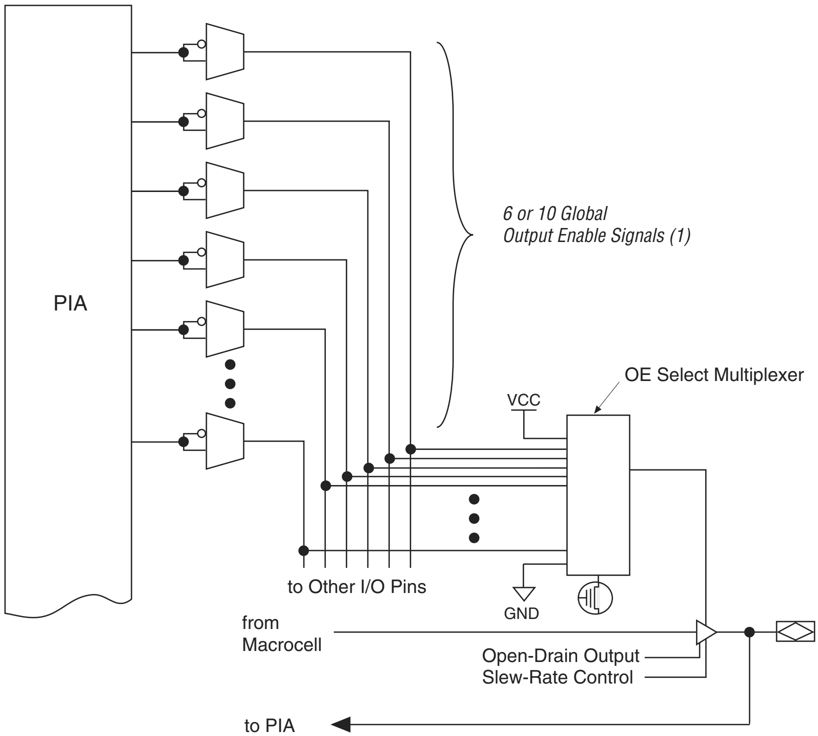
Parallel Expanders

Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell OR logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB.

The Altera development system compiler can automatically allocate up to three sets of up to five parallel expanders to the macrocells that require additional product terms. Each set of five parallel expanders incurs a small, incremental timing delay (t_{PEXP}). For example, if a macrocell requires 14 product terms, the compiler uses the five dedicated product terms within the macrocell and allocates two sets of parallel expanders; the first set includes five product terms, and the second set includes four product terms, increasing the total delay by $2 \times t_{PEXP}$.

Two groups of eight macrocells within each LAB (e.g., macrocells 1 through 8 and 9 through 16) form two chains to lend or borrow parallel expanders. A macrocell borrows parallel expanders from lower–numbered macrocells. For example, macrocell 8 can borrow parallel expanders from macrocell 7, from macrocells 7 and 6, or from macrocells 7, 6, and 5. Within each group of eight, the lowest–numbered macrocell can only lend parallel expanders and the highest–numbered macrocell can only borrow them. Figure 4 shows how parallel expanders can be borrowed from a neighboring macrocell.

Figure 6. I/O Control Block of MAX 3000A Devices



Note:

(1) EPM3032A, EPM3064A, EPM3128A, and EPM3256A devices have six output enables. EPM3512A devices have 10 output enables.

When the tri–state buffer control is connected to ground, the output is tri-stated (high impedance), and the I/O pin can be used as a dedicated input. When the tri–state buffer control is connected to V_{CC}, the output is enabled.

The MAX 3000A architecture provides dual I/O feedback, in which macrocell and pin feedbacks are independent. When an I/O pin is configured as an input, the associated macrocell can be used for buried logic.

Programming Sequence

During in-system programming, instructions, addresses, and data are shifted into the MAX 3000A device through the TDI input pin. Data is shifted out through the TDO output pin and compared against the expected data.

Programming a pattern into the device requires the following six ISP stages. A stand-alone verification of a programmed pattern involves only stages 1, 2, 5, and 6.

1. *Enter ISP*. The enter ISP stage ensures that the I/O pins transition smoothly from user mode to ISP mode. The enter ISP stage requires 1 ms.

2. *Check ID*. Before any program or verify process, the silicon ID is checked. The time required to read this silicon ID is relatively small compared to the overall programming time.

3. *Bulk Erase*. Erasing the device in-system involves shifting in the instructions to erase the device and applying one erase pulse of 100 ms.

4. *Program*. Programming the device in-system involves shifting in the address and data and then applying the programming pulse to program the EEPROM cells. This process is repeated for each EEPROM address.

5. *Verify*. Verifying an Altera device in-system involves shifting in addresses, applying the read pulse to verify the EEPROM cells, and shifting out the data for comparison. This process is repeated for each EEPROM address.

6. *Exit ISP*. An exit ISP stage ensures that the I/O pins transition smoothly from ISP mode to user mode. The exit ISP stage requires 1 ms.

Programming Times

The time required to implement each of the six programming stages can be broken into the following two elements:

- A pulse time to erase, program, or read the EEPROM cells.
- A shifting time based on the test clock (TCK) frequency and the number of TCK cycles to shift instructions, address, and data into the device.

By combining the pulse and shift times for each of the programming stages, the program or verify time can be derived as a function of the TCK frequency, the number of devices, and specific target device(s). Because different ISP-capable devices have a different number of EEPROM cells, both the total fixed and total variable times are unique for a single device.

Programming a Single MAX 3000A Device

The time required to program a single MAX 3000A device in-system can be calculated from the following formula:

$$t_{PROG} = t_{PPULSE} + \frac{Cycle_{PTCK}}{f_{TCK}}$$

where: t_{PROG} = Programming time
t_{PPULSE} = Sum of the fixed times to erase, program, and verify the EEPROM cells
$Cycle_{PTCK}$ = Number of TCK cycles to program a device
f_{TCK} = TCK frequency

The ISP times for a stand-alone verification of a single MAX 3000A device can be calculated from the following formula:

$$t_{VER} = t_{VPULSE} + \frac{Cycle_{VTCK}}{f_{TCK}}$$

where: t_{VER} = Verify time
t_{VPULSE} = Sum of the fixed times to verify the EEPROM cells
$Cycle_{VTCK}$ = Number of TCK cycles to verify a device

The programming times described in Tables 4 through 6 are associated with the worst-case method using the enhanced ISP algorithm.

Table 4. MAX 3000A t_{PULSE} & $Cycle_{TCK}$ Values

Device	Programming		Stand-Alone Verification	
	t_{PPULSE} (s)	$Cycle_{PTCK}$	t_{VPULSE} (s)	$Cycle_{VTCK}$
EPM3032A	2.00	55,000	0.002	18,000
EPM3064A	2.00	105,000	0.002	35,000
EPM3128A	2.00	205,000	0.002	68,000
EPM3256A	2.00	447,000	0.002	149,000
EPM3512A	2.00	890,000	0.002	297,000

Tables 5 and 6 show the in-system programming and stand alone verification times for several common test clock frequencies.

Table 5. MAX 3000A In-System Programming Times for Different Test Clock Frequencies

Device	f_{TCK}								Units
	10 MHz	5 MHz	2 MHz	1 MHz	500 kHz	200 kHz	100 kHz	50 kHz	
EPM3032A	2.01	2.01	2.03	2.06	2.11	2.28	2.55	3.10	s
EPM3064A	2.01	2.02	2.05	2.11	2.21	2.53	3.05	4.10	s
EPM3128A	2.02	2.04	2.10	2.21	2.41	3.03	4.05	6.10	s
EPM3256A	2.05	2.09	2.23	2.45	2.90	4.24	6.47	10.94	s
EPM3512A	2.09	2.18	2.45	2.89	3.78	6.45	10.90	19.80	s

Table 6. MAX 3000A Stand-Alone Verification Times for Different Test Clock Frequencies

Device	f_{TCK}								Units
	10 MHz	5 MHz	2 MHz	1 MHz	500 kHz	200 kHz	100 kHz	50 kHz	
EPM3032A	0.00	0.01	0.01	0.02	0.04	0.09	0.18	0.36	s
EPM3064A	0.01	0.01	0.02	0.04	0.07	0.18	0.35	0.70	s
EPM3128A	0.01	0.02	0.04	0.07	0.14	0.34	0.68	1.36	s
EPM3256A	0.02	0.03	0.08	0.15	0.30	0.75	1.49	2.98	s
EPM3512A	0.03	0.06	0.15	0.30	0.60	1.49	2.97	5.94	s

The instruction register length of MAX 3000A devices is 10 bits. The IDCODE and USERCODE register length is 32 bits. Tables 8 and 9 show the boundary–scan register length and device IDCODE information for MAX 3000A devices.

Table 8. MAX 3000A Boundary–Scan Register Length

Device	Boundary–Scan Register Length
EPM3032A	96
EPM3064A	192
EPM3128A	288
EPM3256A	480
EPM3512A	624

Table 9. 32–Bit MAX 3000A Device IDCODE Value *Note (1)*

Device	IDCODE (32 bits)			
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer's Identity (11 Bits)	1 (1 Bit) *(2)*
EPM3032A	0001	0111 0000 0011 0010	00001101110	1
EPM3064A	0001	0111 0000 0110 0100	00001101110	1
EPM3128A	0001	0111 0001 0010 1000	00001101110	1
EPM3256A	0001	0111 0010 0101 0110	00001101110	1
EPM3512A	0001	0111 0101 0001 0010	00001101110	1

Notes:
(1) The most significant bit (MSB) is on the left.
(2) The least significant bit (LSB) for all JTAG IDCODEs is 1.

See *Application Note 39 (IEEE 1149.1 (JTAG) Boundary–Scan Testing in Altera Devices)* for more information on JTAG BST.

Table 13. MAX 3000A Device Recommended Operating Conditions

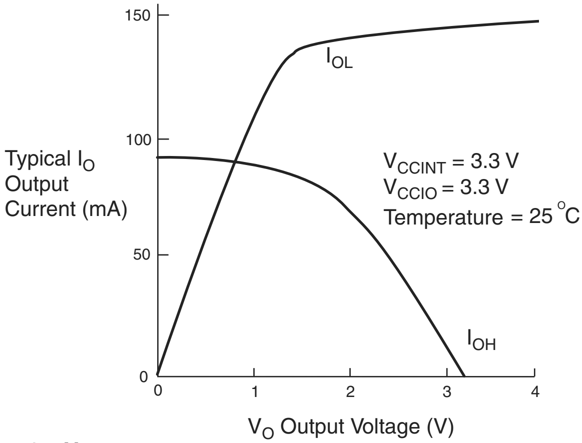
Symbol	Parameter	Conditions	Min	Max	Unit
V_{CCINT}	Supply voltage for internal logic and input buffers	*(10)*	3.0	3.6	V
V_{CCIO}	Supply voltage for output drivers, 3.3–V operation		3.0	3.6	V
	Supply voltage for output drivers, 2.5–V operation		2.3	2.7	V
V_{CCISP}	Supply voltage during ISP		3.0	3.6	V
V_I	Input voltage	*(3)*	–0.5	5.75	V
V_O	Output voltage		0	V_{CCIO}	V
T_A	Ambient temperature	Commercial range	0	70	° C
		Industrial range	–40	85	° C
T_J	Junction temperature	Commercial range	0	90	° C
		Industrial range *(11)*	–40	105	° C
t_R	Input rise time			40	ns
t_F	Input fall time			40	ns

Table 14. MAX 3000A Device DC Operating Conditions *Note (4)*

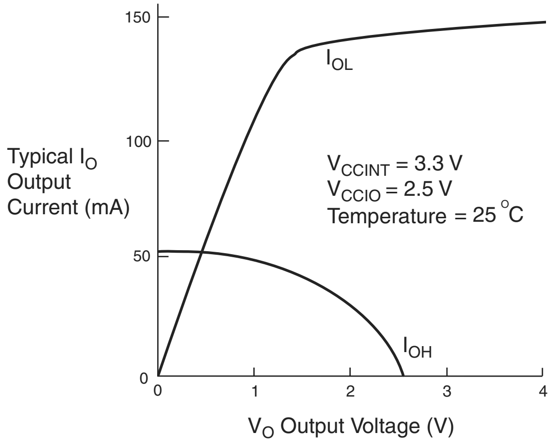
Symbol	Parameter	Conditions	Min	Max	Unit
V_{IH}	High–level input voltage		1.7	5.75	V
V_{IL}	Low–level input voltage		–0.5	0.8	V
V_{OH}	3.3–V high–level TTL output voltage	I_{OH} = –8 mA DC, V_{CCIO} = 3.00 V *(5)*	2.4		V
	3.3–V high–level CMOS output voltage	I_{OH} = –0.1 mA DC, V_{CCIO} = 3.00 V *(5)*	V_{CCIO} – 0.2		V
	2.5–V high–level output voltage	I_{OH} = –100 µA DC, V_{CCIO} = 2.30 V *(5)*	2.1		V
		I_{OH} = –1 mA DC, V_{CCIO} = 2.30 V *(5)*	2.0		V
		I_{OH} = –2 mA DC, V_{CCIO} = 2.30 V *(5)*	1.7		V
V_{OL}	3.3–V low–level TTL output voltage	I_{OL} = 8 mA DC, V_{CCIO} = 3.00 V *(6)*		0.4	V
	3.3–V low–level CMOS output voltage	I_{OL} = 0.1 mA DC, V_{CCIO} = 3.00 V *(6)*		0.2	V
	2.5–V low–level output voltage	I_{OL} = 100 µA DC, V_{CCIO} = 2.30 V *(6)*		0.2	V
		I_{OL} = 1 mA DC, V_{CCIO} = 2.30 V *(6)*		0.4	V
		I_{OL} = 2 mA DC, V_{CCIO} = 2.30 V *(6)*		0.7	V
I_I	Input leakage current	V_I = –0.5 to 5.5 V *(7)*	–10	10	µA
I_{OZ}	Tri–state output off–state current	V_I = –0.5 to 5.5 V *(7)*	–10	10	µA
R_{ISP}	Value of I/O pin pull–up resistor when programming in–system or during power–up	V_{CCIO} = 2.3 to 3.6 V *(8)*	20	74	kΩ

Figure 9. Output Drive Characteristics of MAX 3000A Devices

3.3 V



2.5 V



Power Sequencing & Hot–Socketing

Because MAX 3000A devices can be used in a mixed–voltage environment, they have been designed specifically to tolerate any possible power–up sequence. The V_{CCIO} and V_{CCINT} power planes can be powered in any order.

Signals can be driven into MAX 3000A devices before and during power-up without damaging the device. In addition, MAX 3000A devices do not drive out during power-up. Once operating conditions are reached, MAX 3000A devices operate as specified by the user.

Table 17. EPM3032A Internal Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			–4		–7		–10		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.7		1.2		1.5	ns
t_{IO}	I/O input pad and buffer delay			0.7		1.2		1.5	ns
t_{SEXP}	Shared expander delay			1.9		3.1		4.0	ns
t_{PEXP}	Parallel expander delay			0.5		0.8		1.0	ns
t_{LAD}	Logic array delay			1.5		2.5		3.3	ns
t_{LAC}	Logic control array delay			0.6		1.0		1.2	ns
t_{IOE}	Internal output enable delay			0.0		0.0		0.0	ns
t_{OD1}	Output buffer and pad delay, slow slew rate = off V_{CCIO} = 3.3 V	C1 = 35 pF		0.8		1.3		1.8	ns
t_{OD2}	Output buffer and pad delay, slow slew rate = off V_{CCIO} = 2.5 V	C1 = 35 pF		1.3		1.8		2.3	ns
t_{OD3}	Output buffer and pad delay, slow slew rate = on V_{CCIO} = 2.5 V or 3.3 V	C1 = 35 pF		5.8		6.3		6.8	ns
t_{ZX1}	Output buffer enable delay, slow slew rate = off V_{CCIO} = 3.3 V	C1 = 35 pF		4.0		4.0		5.0	ns
t_{ZX2}	Output buffer enable delay, slow slew rate = off V_{CCIO} = 2.5 V	C1 = 35 pF		4.5		4.5		5.5	ns
t_{ZX3}	Output buffer enable delay, slow slew rate = on V_{CCIO} = 2.5 V or 3.3 V	C1 = 35 pF		9.0		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0	ns
t_{SU}	Register setup time		1.3		2.0		2.8		ns
t_H	Register hold time		0.6		1.0		1.3		ns
t_{RD}	Register delay			0.7		1.2		1.5	ns
t_{COMB}	Combinatorial delay			0.6		1.0		1.3	ns
t_{IC}	Array clock delay			1.2		2.0		2.5	ns
t_{EN}	Register enable time			0.6		1.0		1.2	ns
t_{GLOB}	Global control delay			0.8		1.3		1.9	ns
t_{PRE}	Register preset time			1.2		1.9		2.6	ns
t_{CLR}	Register clear time			1.2		1.9		2.6	ns

Table 17. EPM3032A Internal Timing Parameters (Part 2 of 2) *Note (1)*									
Symbol	**Parameter**	**Conditions**	**Speed Grade**						**Unit**
			–4		**–7**		**–10**		
			Min	**Max**	**Min**	**Max**	**Min**	**Max**	
t_{PIA}	PIA delay	*(2)*		0.9		1.5		2.1	ns
t_{LPA}	Low–power adder	*(5)*		2.5		4.0		5.0	ns

Table 18. EPM3064A External Timing Parameters *Note (1)*									
Symbol	**Parameter**	**Conditions**	**Speed Grade**						**Unit**
			–4		**–7**		**–10**		
			Min	**Max**	**Min**	**Max**	**Min**	**Max**	
t_{PD1}	Input to non–registered output	C1 = 35 pF *(2)*		4.5		7.5		10.0	ns
t_{PD2}	I/O input to non–registered output	C1 = 35 pF *(2)*		4.5		7.5		10.0	ns
t_{SU}	Global clock setup time	*(2)*	2.8		4.7		6.2		ns
t_{H}	Global clock hold time	*(2)*	0.0		0.0		0.0		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF	1.0	3.1	1.0	5.1	1.0	7.0	ns
t_{CH}	Global clock high time		2.0		3.0		4.0		ns
t_{CL}	Global clock low time		2.0		3.0		4.0		ns
t_{ASU}	Array clock setup time	*(2)*	1.6		2.6		3.6		ns
t_{AH}	Array clock hold time	*(2)*	0.3		0.4		0.6		ns
t_{ACO1}	Array clock to output delay	C1 = 35 pF *(2)*	1.0	4.3	1.0	7.2	1.0	9.6	ns
t_{ACH}	Array clock high time		2.0		3.0		4.0		ns
t_{ACL}	Array clock low time		2.0		3.0		4.0		ns
t_{CPPW}	Minimum pulse width for clear and preset	*(3)*	2.0		3.0		4.0		ns
t_{CNT}	Minimum global clock period	*(2)*		4.5		7.4		10.0	ns
f_{CNT}	Maximum internal global clock frequency	*(2)*, *(4)*	222.2		135.1		100.0		MHz
t_{ACNT}	Minimum array clock period	*(2)*		4.5		7.4		10.0	ns
f_{ACNT}	Maximum internal array clock frequency	*(2)*, *(4)*	222.2		135.1		100.0		MHz

Table 19. EPM3064A Internal Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			–4		–7		–10		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.6		1.1		1.4	ns
t_{IO}	I/O input pad and buffer delay			0.6		1.1		1.4	ns
t_{SEXP}	Shared expander delay			1.8		3.0		3.9	ns
t_{PEXP}	Parallel expander delay			0.4		0.7		0.9	ns
t_{LAD}	Logic array delay			1.5		2.5		3.2	ns
t_{LAC}	Logic control array delay			0.6		1.0		1.2	ns
t_{IOE}	Internal output enable delay			0.0		0.0		0.0	ns
t_{OD1}	Output buffer and pad delay, slow slew rate = off V_{CCIO} = 3.3 V	C1 = 35 pF		0.8		1.3		1.8	ns
t_{OD2}	Output buffer and pad delay, slow slew rate = off V_{CCIO} = 2.5 V	C1 = 35 pF		1.3		1.8		2.3	ns
t_{OD3}	Output buffer and pad delay, slow slew rate = on V_{CCIO} = 2.5 V or 3.3 V	C1 = 35 pF		5.8		6.3		6.8	ns
t_{ZX1}	Output buffer enable delay, slow slew rate = off V_{CCIO} = 3.3 V	C1 = 35 pF		4.0		4.0		5.0	ns
t_{ZX2}	Output buffer enable delay, slow slew rate = off V_{CCIO} = 2.5 V	C1 = 35 pF		4.5		4.5		5.5	ns
t_{ZX3}	Output buffer enable delay, slow slew rate = on V_{CCIO} = 2.5 V or 3.3 V	C1 = 35 pF		9.0		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0	ns
t_{SU}	Register setup time		1.3		2.0		2.9		ns
t_{H}	Register hold time		0.6		1.0		1.3		ns
t_{RD}	Register delay			0.7		1.2		1.6	ns
t_{COMB}	Combinatorial delay			0.6		0.9		1.3	ns
t_{IC}	Array clock delay			1.2		1.9		2.5	ns
t_{EN}	Register enable time			0.6		1.0		1.2	ns
t_{GLOB}	Global control delay			1.0		1.5		2.2	ns
t_{PRE}	Register preset time			1.3		2.1		2.9	ns

Table 21. EPM3128A Internal Timing Parameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			–5		–7		–10		
			Min	Max	Min	Max	Min	Max	
t_{SU}	Register setup time		1.4		2.1		2.9		ns
t_{H}	Register hold time		0.6		1.0		1.3		ns
t_{RD}	Register delay			0.8		1.2		1.6	ns
t_{COMB}	Combinatorial delay			0.5		0.9		1.3	ns
t_{IC}	Array clock delay			1.2		1.7		2.2	ns
t_{EN}	Register enable time			0.7		1.0		1.3	ns
t_{GLOB}	Global control delay			1.1		1.6		2.0	ns
t_{PRE}	Register preset time			1.4		2.0		2.7	ns
t_{CLR}	Register clear time			1.4		2.0		2.7	ns
t_{PIA}	PIA delay	*(2)*		1.4		2.0		2.6	ns
t_{LPA}	Low–power adder	*(5)*		4.0		4.0		5.0	ns

Table 22. EPM3256A External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			–7		–10		
			Min	Max	Min	Max	
t_{PD1}	Input to non–registered output	C1 = 35 pF *(2)*		7.5		10	ns
t_{PD2}	I/O input to non–registered output	C1 = 35 pF *(2)*		7.5		10	ns
t_{SU}	Global clock setup time	*(2)*	5.2		6.9		ns
t_{H}	Global clock hold time	*(2)*	0.0		0.0		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF	1.0	4.8	1.0	6.4	ns
t_{CH}	Global clock high time		3.0		4.0		ns
t_{CL}	Global clock low time		3.0		4.0		ns
t_{ASU}	Array clock setup time	*(2)*	2.7		3.6		ns
t_{AH}	Array clock hold time	*(2)*	0.3		0.5		ns
t_{ACO1}	Array clock to output delay	C1 = 35 pF *(2)*	1.0	7.3	1.0	9.7	ns
t_{ACH}	Array clock high time		3.0		4.0		ns
t_{ACL}	Array clock low time		3.0		4.0		ns
t_{CPPW}	Minimum pulse width for clear and preset	*(3)*	3.0		4.0		ns

Table 23. EPM3256A Internal Timing Parameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			–7		–10		
			Min	Max	Min	Max	
t_{ZX3}	Output buffer enable delay, slow slew rate = on V_{CCIO} = 2.5 V or 3.3 V	C1 = 35 pF		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	C1 = 5 pF		4.0		5.0	ns
t_{SU}	Register setup time		2.1		2.9		ns
t_{H}	Register hold time		0.9		1.2		ns
t_{RD}	Register delay			1.2		1.6	ns
t_{COMB}	Combinatorial delay			0.8		1.2	ns
t_{IC}	Array clock delay			1.6		2.1	ns
t_{EN}	Register enable time			1.0		1.3	ns
t_{GLOB}	Global control delay			1.5		2.0	ns
t_{PRE}	Register preset time			2.3		3.0	ns
t_{CLR}	Register clear time			2.3		3.0	ns
t_{PIA}	PIA delay	*(2)*		2.4		3.2	ns
t_{LPA}	Low–power adder	*(5)*		4.0		5.0	ns

Table 24. EPM3512A External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			-7		-10		
			Min	Max	Min	Max	
t_{PD1}	Input to non-registered output	C1 = 35 pF *(2)*		7.5		10.0	ns
t_{PD2}	I/O input to non-registered output	C1 = 35 pF *(2)*		7.5		10.0	ns
t_{SU}	Global clock setup time	*(2)*	5.6		7.6		ns
t_{H}	Global clock hold time	*(2)*	0.0		0.0		ns
t_{FSU}	Global clock setup time of fast input		3.0		3.0		ns
t_{FH}	Global clock hold time of fast input		0.0		0.0		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF	1.0	4.7	1.0	6.3	ns
t_{CH}	Global clock high time		3.0		4.0		ns
t_{CL}	Global clock low time		3.0		4.0		ns
t_{ASU}	Array clock setup time	*(2)*	2.5		3.5		ns

Table 25. EPM3512A Internal Timing Parameters (Part 2 of 2) *Note (1)*							
Symbol	Parameter	Conditions	Speed Grade				Unit
			-7		-10		
			Min	Max	Min	Max	
t_{OD3}	Output buffer and pad delay, slow slew rate = on V_{CCIO} = 2.5 V or 3.3 V	C1 = 35 pF		6.0		6.5	ns
t_{ZX1}	Output buffer enable delay, slow slew rate = off V_{CCIO} = 3.3 V	C1 = 35 pF		4.0		5.0	ns
t_{ZX2}	Output buffer enable delay, slow slew rate = off V_{CCIO} = 2.5 V	C1 = 35 pF		4.5		5.5	ns
t_{ZX3}	Output buffer enable delay, slow slew rate = on V_{CCIO} = 3.3 V	C1 = 35 pF		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	C1 = 5 pF		4.0		5.0	ns
t_{SU}	Register setup time		2.1		3.0		ns
t_H	Register hold time		0.6		0.8		ns
t_{FSU}	Register setup time of fast input		1.6		1.6		ns
t_{FH}	Register hold time of fast input		1.4		1.4		ns
t_{RD}	Register delay			1.3		1.7	ns
t_{COMB}	Combinatorial delay			0.6		0.8	ns
t_{IC}	Array clock delay			1.8		2.3	ns
t_{EN}	Register enable time			1.0		1.3	ns
t_{GLOB}	Global control delay			1.7		2.2	ns
t_{PRE}	Register preset time			1.0		1.4	ns
t_{CLR}	Register clear time			1.0		1.4	ns
t_{PIA}	PIA delay	*(2)*		3.0		4.0	ns
t_{LPA}	Low-power adder	*(5)*		4.5		5.0	ns

Notes to tables:

(1) These values are specified under the recommended operating conditions, as shown in Table 13 on page 23. See Figure 11 on page 27 for more information on switching waveforms.

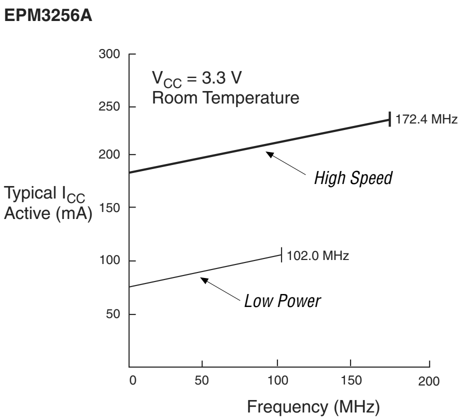
(2) These values are specified for a PIA fan–out of one LAB (16 macrocells). For each additional LAB fan–out in these devices, add an additional 0.1 ns to the PIA timing value.

(3) This minimum pulse width for preset and clear applies for both global clear and array controls. The t_{LPA} parameter must be added to this minimum width if the clear or reset signal incorporates the t_{LAD} parameter into the signal path.

(4) These parameters are measured with a 16–bit loadable, enabled, up/down counter programmed into each LAB.

(5) The t_{LPA} parameter must be added to the t_{LAD}, t_{LAC}, t_{IC}, t_{EN}, t_{SEXP}, $\mathbf{t_{ACL}}$, and $\mathbf{t_{CPPW}}$ parameters for macrocells running in low–power mode.

Figure 13. I_{CC} vs. Frequency for MAX 3000A Devices



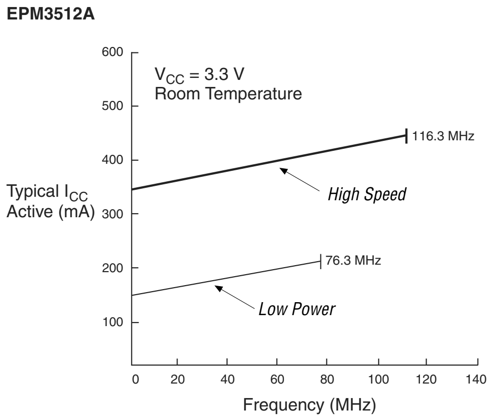


Figure 15. 100–Pin TQFP Package Pin–Out Diagram

Package outline not drawn to scale.

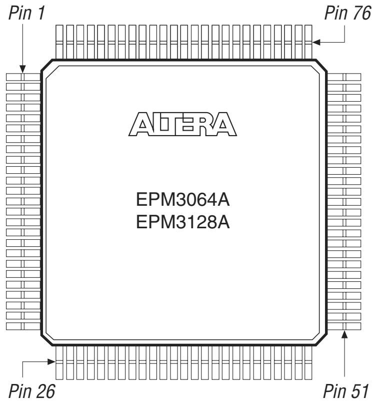
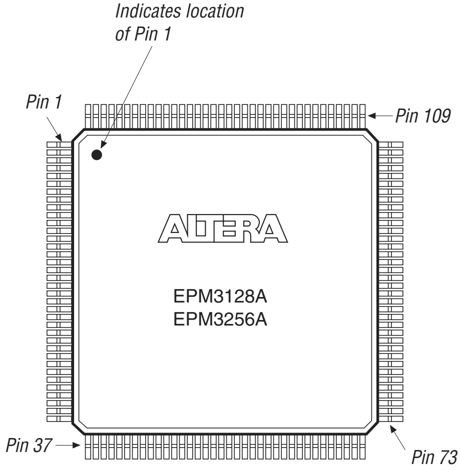


Figure 16. 144–Pin TQFP Package Pin–Out Diagram

Package outline not drawn to scale.



Version 3.3

The following changes were made in the *MAX 3000A Programmable Logic Device Data Sheet* version 3.3:

- Updated Tables 3, 13, and 26.
- Added Tables 4 through 6.
- Updated Figures 12 and 13.
- Added "Programming Sequence" on page 14 and "Programming Times" on page 14

Version 3.2

The following change were made in the *MAX 3000A Programmable Logic Device Data Sheet* version 3.2:

- Updated the EPM3512 I_{CC} versus frequency graph in Figure 13.

Version 3.1

The following changes were made in the *MAX 3000A Programmable Logic Device Data Sheet* version 3.1:

- Updated timing information in Table 1 for the EPM3256A device.
- Updated *Note (10)* of Table 15.

Version 3.0

The following changes were made in the *MAX 3000A Programmable Logic Device Data Sheet* version 3.0:

- Added EPM3512A device.
- Updated Tables 2 and 3.

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